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|-----------------------------------|---------------------------------------|--|-------------|
| <b>Notice of References Cited</b> | Application/Control No.<br>10/784,134 | Applicant(s)/Patent Under<br>Reexamination<br>FRANKOWSKY, GERD |             |
|                                   | Examiner<br>Cynthia Britt             | Art Unit<br>2117   | Page 1 of 1 |

**U.S. PATENT DOCUMENTS**

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|   | V | Automatic In-Line Measurement for the Identification of Killer Defects by Wilson et al. Presented at ICMTS 1994 |
|   | W |   |
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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